Atomic contrast on ultrathin La_{0.7}Sr_{0.3}MnO₃ films by Scanning Tunnelling Microscopy

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Summary

In this work we map tunnel conductance curves and topographies with nanometric and sub-nanometric spatial resolution of fully insulating $La_{0.7}Sr_{0.3}MnO_3$ ultrathin films at room temperature. While spectroscopy shows the lack of spatial patterns, suggesting no strong correlation between topographic and spectroscopic features at room temperature, we obtained for the first time clear atomic contrast at only some surface locations. We justify our results by suggesting the presence of local intrinsic inhomogeneities, that would act on a surface with overall homogeneous electronic states as charge density reliever, by allowing atomic contrast by a tunnelling measurement. Furthermore, our findings suggest that the effect of strain is to induce a transition from weak- to strong-electron-phonon coupling regimes, making fully-strained films as interesting model-systems to investigate the nature of the electron correlation directly at nanoscale lengths.

Key words: manganites, STM, ultrathin films, highly correlated systems, atomic resolution.

Introduction

Perovskite manganites, having general formula $Re_{1-x}A_{x}MnO_{3}$ (where Re = Rare Earth, A =Divalent metal) have been often studied by Microscopy Scanning Tunnelling and Spectroscopy (STM-STS) techniques. Indeed, investigation of surface states with nanoscale resolution is strongly desirable on such highly-correlated systems, whose exotic properties arise from the coexistence of microscopic effects (Dagotto et al., 2001). According to the definition given by Postorino (Postorino et al., 2003) and based on the classification made by Millis (Millis et al., 1996), perovskite manganites can be ordered according to three classes depending on the strength of the electron-phonon coupling. Manganites belonging to weak and intermediate *coupling* exhibit ferromagnetic (FM) to paramagnetic (PM) phase transition at the temperature T_c ; above T_c the transport is believed to be governed by polarons due to strong phonon-electron coupling, mediated by Jahn-Teller distortion around the trivalent Mn^{3+} ion. Below T_c the ground state

is metallic $(d\rho/dT > 0)$. The transition from the activated PM state to the metallic FM state is referred to as the Metal-Insulator-Transition (MIT). Strong coupled manganites do not exhibit MIT and are insulating over the whole range of temperature, although PM-FM transitions occur at temperatures depending on doping and/or composition. The study of the variation around the MIT of the density of states at the Fermi level $N_{S}(E_{F})$ has constituted the main topic of investigation for many STM-STS experiments. Early works on thin films (Fath et al., 1999; Becker et al., 2002) were focused on the features of coexistence of carrier-rich FM metallic and carrier-deficient non-FM insulating regions up to the mesoscopic scale. Such phenomenon is known as electronic phase-separation (PS). The topographic contrast was used to distinguish between occupied and unoccupied states on epitaxial 120 nm thick film of La_{5/8-0.3}Pr_{0.3}Ca_{5/8}MnO₃ (Ma *et al.*, 2005) and $Bi_{0.24}Ca_{0.76}MnO_3$ single crystals (Renner et al., 2002). Then, atomic contrast was proposed as marker for polaron confinement at the surface in layered rock-salt type manganites (RØnnow et

al., 2006; Bryat et al., 2011), as well as in cubic Pr_{0.68}Pb_{0.32}MnO₃ (Rößler et al., 2010). It is noteworthy that atomic contrast was obtained on manganese perovskite compounds belonging to the strong coupling class only, with the exception of the Pr_{0.68}Pb_{0.32}MnO₃ which comes from the intermediate coupling class. On the other hand, robust STS measurements on epitaxial La_{0.7}Ca_{0.3}Mn_{O3} (LCMO) (Seiro *et al.*, 2010; Mitra *et* al., 2005) or La_{0.7}Sr_{0.3}MnO₃ (LSMO) thin films (Singh et al., 2008) found an homogeneous spectroscopic behaviour which suggested that no polarons are confined on both sides of the MIT (Seiro et al., 2008). Nonetheless, scanning tunnelling experiments on such systems are useful to investigate the nature of the charge localization effect at the surface, still controversial to date. In bulky manganites, despite the low - if compared to metals – density of carriers ($\sim 10^{21}$ cm⁻³), charge screening was indicated as a strong limiting factor on the maximum lateral resolution obtainable by STM (RØnnow et al., 2006); anyway, by reviewing the works presented so far, it is not clear whether polarons, lattice inhomogeneities having a purely morphological origin, as well as intrinsic point defects, can be treated separately. Attempting to address these controversial aspects, we performed for the first time an extensive STM characterization on ultrathin manganite films. The striking difference between bulks and films arises from the film thickness; when it is reduced under a critical value (t_c) , they show the lack of the MIT and fully-insulating behaviour regardless the temperature (Huijben et al., 2008; Jin et al., 2007). Surprisingly, scanning probe investigations on ultrathin manganite films (few unit cells thick) are rare (Rana et al., 2010), despite of the interest into ultrathin epitaxial films (2D) where small changes in structure or composition affect significantly the electronic structure and therefore the macroscopic properties (Huijben et al., 2008; Bergenti et al., 2007). Transport and and magneto-optical measurements performed on ultrathin manganite films (Aruta et al., 2009; Orgiani et al., 2007) have remarked the role played by chemical or structural inhomogeneities, such as point defects and/or intrinsic lattice deformations. In this topic, fullystrained manganite films represent an interesting model-system for high-resolution STM analysis either for the electronic contrast mechanism or the direct investigation of inhomogeneities, since charge screening is expected to be naturally reduced *a priori* by the poor surface conductivity, similarly to what happens in semiconductors where resolution of individual atoms is related to the presence of localized electronic states on the surface around E_F , which contribute as local variations in the probing tunnel current.

Materials and Methods

Here we present an STM characterization of two doped La_{0.7}Sr_{0.3}MnO₃ (LSMO) films -5 and -9 unit cells thick, respectively deposited on cubic (a =3.90Å) SrTiO₃ (STO) substrates. This compound shows Colossal Magneto Resistance (CMR) effect at high temperatures and was successfully employed in the form of epitaxial films in the fabrication of spin-transport-based devices (Preziosi et al., 2011; Barraud et al., 2010). LSMO films were grown by Channel Spark Ablation technique, already used to produce epitaxial films as described elsewhere (Bergenti et al., 2007; Dediu et al., 1999). Film thicknesses were evaluated by X-Ray Reflectivity (XRR) measurements. Bulk $La_{0.7}Sr_{0.3}MnO_3$ is rhombohedral at room temperature, having pseudocubic parameter $a=3.873\text{\AA}$ and a distorted pseudocubic angle α = 90.26° (Trukhanov et al., 2007). The STM-STS measurements were carried out at 298K and Ultra High Vacuum (UHV) conditions by using a commercial instrument. After being transferred into UHV chamber, samples were heated in-situ at 120°C for a few hours, and successively left to cool for many hours before the measurements. Cut PtIr wires tips were used and the surfaces imaged mainly in the topographic mode with an applied tip-biased voltage of ~1V. Setpoint current of 100-120 pA was required to achieve atomic contrast on both samples. The measurement parameters were adjusted repeatedly in order to reduce artefacts due to the scan operation and thermal drift distortion. DC Transport measurements were performed by a cryogenic apparatus with four-probe method. As shown in Figure 1d, our ultrathin films experience the lack of the MIT as expected for fully strained samples, on the whole temperature range. Despite of the high spatial resolution (up to 1 nm²), the strong reproducibility and the good (40 meV) energy resolution of STS measurements, our I(V) curves should be taken an indication of the surface spec-



Figure 1. a) Constant current image of a 1 x 1 μ 2 region taken on a 5 u.c. thick sample showing a largely terraced surface. b) Z-profile taken along the blue path on image a), showing that peak-to-peak roughness variations are within \pm 1 u.c. (~ 0.4 nm). c) Resistance vs Temperature curves plotted for three different film of thicknesses, showing the lack of the MIT when thickness is under 6 nm, as samples under our investigation. d) Bare I(V) and corresponding dI/dV characteristics recorded over the surface in a) at RT; each curve is obtained by an average of 36 curves recorded within a single 60 x 60 nm2 large region, (the spectroscopy spatial resolution being 10×10 nm²/spectrum), at the locations labelled by squares on image a). Topography and I(V) curves were measured at regulation conditions of 1V and 0.1 nA.

troscopy, rather than a direct estimation of the local Density of States (DOS). It is known that the tunnelling relation

$$\frac{dI}{dV}\approx \frac{e^2}{\hbar^2}\rho_s(eV)\rho_T(0)T(e,V,z),$$

would be more appropriate in this case (Stroscio *et al.*), but it requires higher energy resolution, which is normally associated to criogenic measurements.

Results

where ρ_s (eV) is the sample DOS, ρ_l (0) is the tip DOS and T(e, V, z) is the tunnelling coefficient within the barrier, is valid at low $(eV << \phi)$ biases, with ϕ = work function, whereas T(e, V, z) does not depends on the energy (Tersoff and Hamann 1983). Moreover, it should be noted that curve representation as logarithmic derivative dlnI/dlnV

A typical topography showing a $1 \times 1 \ \mu m^2$ large sample region is presented in Fig. 1a. It reveals growth terraces roughly 100-200 nm wide, having steps of height about 1 unit cell (Figure 1b). Moreover we observed the absence of outgrowth up to $5 \times 5 \ \mu m^2$ large areas. Note that on these scales it is not possible to indicate a unique terminating plane in the whole surface. The measurements show the Root Mean Square (RMS) roughness on both 5 and 9 u.c. thick samples being about one half of unit cell (~ 0.2 nm). Figure 1d shows the averaged tunnelling spectroscopy curves performed at 9 positions above the surface; curves were acquired simultaneously with imaging, and the exact locations are shown in the topographic image in a). Even near to terrace steps, local I(V) curves show the lack of spatial patterns in the energy range investigated, suggesting no strong correlation between topographic and spectroscopic features at room temperature. The surface is constituted by grains having a slightly mounded shape, 10-20 nm wide and a few cells high, as shown in Figure 2a, whose presence was already recognized among manganites grown by Pulsed Laser Deposition technique (Seiro et al., 2008). Note that the dimensions of these mounds tend to slightly increase with the film thickness, although we observed no significant changes of morphology from the insulating toward the semi-metallic thickness regime (Singh et al., 2008). Figure 2 shows the averaged I(V) and dI/dV curves taken on a 30×30 nm² regions, where mounds are clearly visible. Note that the increased spatial resolution reveals some differences between the curves acquired among different image locations, especially for negative biases. This discrepancies were observed before on a 5 nm thick LSMO film on larger scales, and ascribed to local stress of topographic steps that distort the lattice and disperse the electronic states (Rana *et al.*, 2010). We obtained clear atomic contrast at room temperature on both 5 and 9 u.c. thick samples, by visualizing the unit cell, as shown in the Figures 3 and 4. Nevertheless, we observed that the atomic contrast is limited to only few small (a few square nanometers) regions upon the samples surface.

Discussion and Conclusions

Among the scales investigated in this work, previous reports have already shown the absence of nanoscale modulation around the MIT on LSMO (Singh *et al.*, 2008; Seiro *et al.*, 2007; Seiro *et al.*, 2008) or only small variations (Rana *et al.*, 2010). The absence of an extrinsic phase separation lead to consider the spatial average of I(V) curves as representative of the whole sample surface. Findings of atomic contrast in Figure 3a,b and c, related to the 5 cell thick sample seems to suggest that a localised impurity or defect whose field locally may relieve the charge screening upon a length of some or tens of nm allows atomic resolution on such a region. This picture is supported



Figure 2. Averaged I(V) and corresponding dI/dV curves taken on the region 30×30 nm² in the inset at the 9 indicated positions. This region was taken within the region in Figure 1a. The surface granular structure is clearly visible but no direct evidence of correlation between spectra and topographic features is found, although spectra show quite different behaviour at negative biases.



Figure 3. a), b), c), d) Atomically resolved images on a 5 cells-thick LSMO/STO sample. Different orientations of the atomic layers are found on three different regions located at about 5-10 nm of distance each others. Note the presence of defects (more darker or brighter regions) having maximum step heights of about 0.4 nm. In d) an image of a typical unit cell having distorted shape is shown, taken on a fourth region (not reported here entirely). Topographies were recorded at $V_{\rm bias} = 1.2V$, I =120 pA.



Figure 4. a) 12×12 nm² topography over the 9 u.c. thick sample. Atomic contrast is more clearly visible near to the terraces boundaries and over more internal regions located close to "huge" defects as in b) were a detail of a) is shown. c) The proposed mechanism for the charge relieving.

by our findings on the 9 cell thick sample, and shown in Figure 4, on a 13×13 nm² area. Atomic contrast is obtained especially close to topographic steps or mounds boundary, -the latter is expected to be a source of mismatch defects-, that may act as local scattering centres and locally favour the atomic resolution, even on an atomically flat surface and in presence of quite homogeneous surface conduction, as supported by our I(V) characteristics. We therefore suggest that surface inhomogeneities may locally increase the charge localization, by allowing or participating to the atomic contrast in a tunnelling measurements. One may infer that among bulks, inhomogeneities act *ipso facto* as the counterpart of the metallicity in surface state localization. As a further consideration, we often observed a strongly distorted cell, as clearly visible from the Figure 3 and 4, whose interatomic distances appear often quite different with respect to the picture of a square cell, as commonly assumed in literature. These distortions are evident in some regions on the 5 u.c. thick sample, and seem to be linked to local surface features rather than to scan/thermal drift effects, that are controlled to any possible extent. Cell distortions might be explained by the presence of intrinsic Moiré patterns, due to a interference coupling between the topmost and the inner atomic layer. It is clear that this occurrence would indicates by itself the presence of lattice discontinuities; however, this hypothesis is hardly justifiable due to the unclearness of the relieving mechanism, especially out-of-plane. Otherwise, we observed that the growth mode favours at the top layer the formation on non-uniform and atomically-stepped regions where, the surface reconstruction is not complete. In other words, the film growth appears epitaxial and coherent unless the last few atomic layer near the surface, making the presence of local defects related only to surface reconstruction. It is possible that these defects may act as scattering centres for the charge relieving, in the sense described above, and occasionally cause local strong lattice distortions as those shown in Figure 3. In reason of this, we suggest that the observed cell distortions are originated by an incomplete surface reconstruction. In conclusion, it is remarkable that bulk LSMO belongs to the weak coupling class, i.e. a family of manganese perovskite where people never succeeded in obtaining STM atomic resolution. We are able to affirm, thus, that the substrate-induced strain induces a so higher e-ph coupling that the materials is thrown in another class of manganese perovskite compounds, the strong coupling one (or phase segregated), which does not feature MIT and allowed for STM atomic contrast for the reasons discussed previously. Fully strained manganite thin films reveal to be an excellent tool to manipulate the physical state of the manganese perovskites playing with *e-ph* coupling and MIT, offering optimal candidates for basic solid state physics. In our experience, no surface preparation was required to achieve these results that were obtained at basic environmental and experimental conditions.

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